

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No 05542-459005	Application No 09/909,766
<b>Information Disclosure Statement</b> <b>by Applicant</b> (Use several sheets if necessary) JUN 10 2002 (37 CFR §1.98(b))		Applicant Wallace T.Y. Tang	
		Filing Date July 19, 2001	Group Art Unit Unknown

### Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AAAAA	62-190728	08/20/87	Japan			Abstr.	
	BBBBB	62-211927	09/17/87	Japan			Abstr.	
	CCCCC	62-283678	12/09/87	Japan			Abstr.	
	DDDDD	63-256344	10/24/88	Japan			Abstr.	
	EEEEE	259938	06/10/89	Japan			Abstr.	
	FFFFF	2-222533	09/05/90	Japan			Abstr.	
	GGGGG	3-234467	10/18/91	Japan			Yes	
	HHHHH	5-138531	06/01/93	Japan			Abstr.	
	IIIII	5-309558	11/22/93	Japan			Yes	
	JJJJJ	7-52032	02/28/95	Japan			Yes	
	KKKKK	WO 93/20976	10/28/93	WIPO				

### Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	ALLLL	Anonymous, "End-Point Detection of Oxide Polishing and Planarization of Semiconductor Devices," Research Disclosure, 1992, No. 340, Kenneth Mason Publications Ltd., England
	AMMMM	Carotta et al., "Effect of thickness and surface treatment on silicon wafer reflectance," Solar Energy Materials and Solar Cells, 1992, 27:265-272
	ANNNN	Henck, "In situ real-time ellipsometry for film thickness measurement and control," J. Vac. Sci. Technol. A., 1992, 10(4):934-938
	AOOOO	Jurczyk et al., "Process Detection System," IBM Technical Disclosure Bulletin, 1975, 18(6):1867-1870
	APPPP	Nakamura et al., "Mirror Polishing of Silicon Wafers (4 <sup>th</sup> Report)." - Development of Bowl Feed and Double Side Polishing Machine with In-situ Thickness Monitoring of Silicon Wafers, JSPE, pp. 129-134
	AQQQQ	Sautter et al., "Development process control and optimization utilizing an end point monitor," SPIE, 1989, 1087:312-316

Examiner Signature <i>William H. Hines</i>	Date Considered 1/10/03
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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U.S. Patent Documents							
Examiner Initial	Desig ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
JS	ACCC	5,433,651	07/1995	Lustig et al.			
JS	ADDD	5,483,568	01/1996	Yano et al.			
JS	AEEE	5,489,233	02/06/96	Cook et al.			
JS	AFFF	5,499,733	03/1996	Litvak			
JS	AGGG	5,605,760	02/25/97	Roberts			
JS	AHHH	5,609,511	03/11/97	Moriyama et al.			
JS	IIII	5,893,796	04/13/99	Birang et al.			
JS	AJJJ	5,910,043	06/08/99	Manzonic et al.			
JS	AKKK	5,948,259	09/07/99	Deguitre et al.			
JS	ALLL	5,949,927	09/07/99	Tang			
JS	AMMM	5,964,643	10/12/99	Birang et al.			
JS	ANNN	6,045,439	04/04/00	Birang et al.			
JS	AOOO	6,280,290	08/28/01	Birang et al.			

Foreign Patent Documents or Published Foreign Patent Applications								
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							Yes	No
JS	APPP	625,573	08/15/61	Canada				
JS	AQQQ	0 352 740 A2	01/31/90	EPO				
JS	ARRR	0 468 897 A	07/16/91	EPO			Abstr.	
JS	ASSS	0 663 265 A1	07/19/95	EPO				
JS	ATTT	0 738 561 A1	03/28/96	EPO				
JS	AUUU	1,075,634	10/19/54	France			Yes	
JS	AVVV	57-138575	08/26/82	Japan			Abstr.	
JS	AWWW	58-4353	01/11/83	Japan			Abstr.	
JS	AXXX	59-57215	04/1984	Japan				
JS	AYYY	59-74635	04/27/84	Japan			Abstr.	
JS	AZZZ	61-164773	07/25/86	Japan			Abstr.	

Examiner Signature <i>(Signature)</i>	Date Considered 1/14/05
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## U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
ju	ABB	5,069,002	12/1991	Sandhu et al.			
ju	ACC	5,081,421	01/1992	Miller et al.			
ju	ADD	5,081,796	01/1992	Schultz			
ju	AEE	5,097,430	03/17/92	Birang			
ju	AFF	5,120,966	06/1992	Kondo			
ju	AGG	5,132,617	07/21/92	Leach et al.			
ju	AHH	5,177,908	01/12/93	Tuttle			
ju	AII	5,196,353	03/23/93	Sandhu et al.			
ju	AJJ	5,213,655	05/25/93	Leach et al.			
ju	AKK	5,219,787	06/15/93	Carey et al.			
ju	ALL	5,234,868	08/10/93	Cote			
ju	AMM	5,240,552	08/31/93	Yu et al.			
ju	ANN	5,242,524	09/07/93	Leach et al.			
ju	AOO	5,257,478	11/02/93	Hyde et al.			
ju	APP	5,265,378	11/30/93	Rostoker			
ju	AQQ	5,294,289	03/15/94	Heinz et al.			
ju	ARR	5,297,364	03/29/94	Tuttle			
ju	ASS	5,308,438	05/03/94	Cote et al.			
ju	ATT	5,308,447	05/1994	Lewis et al.			
ju	AUU	5,321,304	06/14/94	Rostoker			
ju	AVV	5,329,734	07/19/94	Yu			
ju	AWW	5,332,467	07/26/94	Sune et al.			
ju	AXX	5,337,015	08/09/94	Lustig et al.			
ju	AYY	5,394,655	03/07/95	Allen et al.			
ju	AZZ	5,395,801	03/07/95	Doan et al.			
ju	AAAA	5,413,651	05/09/95	Otruba			
ju	ABBB	5,413,941	05/09/95	Koos et al.			

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*John A. ...*

Date Considered

1/16/03

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Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
W.T.T.	AA	2,578,859	12/1951	Teeple et al.			
W.T.T.	AB	2,973,686	03/1961	Dreyfus et al.			
W.T.T.	AC	3,510,667	05/1970	Cleveland et al.			
W.T.T.	AD	3,623,813	11/1971	Hacman			
W.T.T.	AE	3,630,795	12/1971	Vorie			
W.T.T.	AF	3,986,777	10/1976	Roll			
W.T.T.	AG	4,272,924	06/16/81	Masuko et al.			
W.T.T.	AH	4,328,068	05/04/82	Curtis			
W.T.T.	AI	4,436,367	03/1984	Lewis et al.			
W.T.T.	AJ	4,512,847	04/23/85	Brunsch et al.			
W.T.T.	AK	4,529,986	07/1985	d'Auria et al.			
W.T.T.	AL	4,569,717	02/1986	Ohgami et al.			
W.T.T.	AM	4,618,262	10/1986	Maydan et al.			
W.T.T.	AN	4,672,200	06/1987	Claypool et al.			
W.T.T.	AO	4,711,516	12/1987	Graber			
W.T.T.	AP	4,713,140	12/1987	Tien			
W.T.T.	AQ	4,776,695	10/1988	Van Pham et al.			
W.T.T.	AR	4,793,895	12/1988	Kaanta et al.			
W.T.T.	AS	4,879,258	11/1989	Fisher			
W.T.T.	AT	4,929,828	05/1990	Claypool			
W.T.T.	AU	4,948,259	08/14/90	Enke et al.			
W.T.T.	AV	4,954,142	09/04/90	Carr et al.			
W.T.T.	AW	4,998,021	03/1991	Mimasaka			
W.T.T.	AX	4,999,509	03/1991	Wada et al.			
W.T.T.	AY	5,020,283	06/04/91	Tuttle			
W.T.T.	AZ	5,036,015	07/1991	Sandhu et al.			
W.T.T.	AAA	5,046,849	09/1991	Severin et al.			

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*W.T.T.*

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